

# WISE Operations MMR

## IPAC/WSDS Weekly Status Report

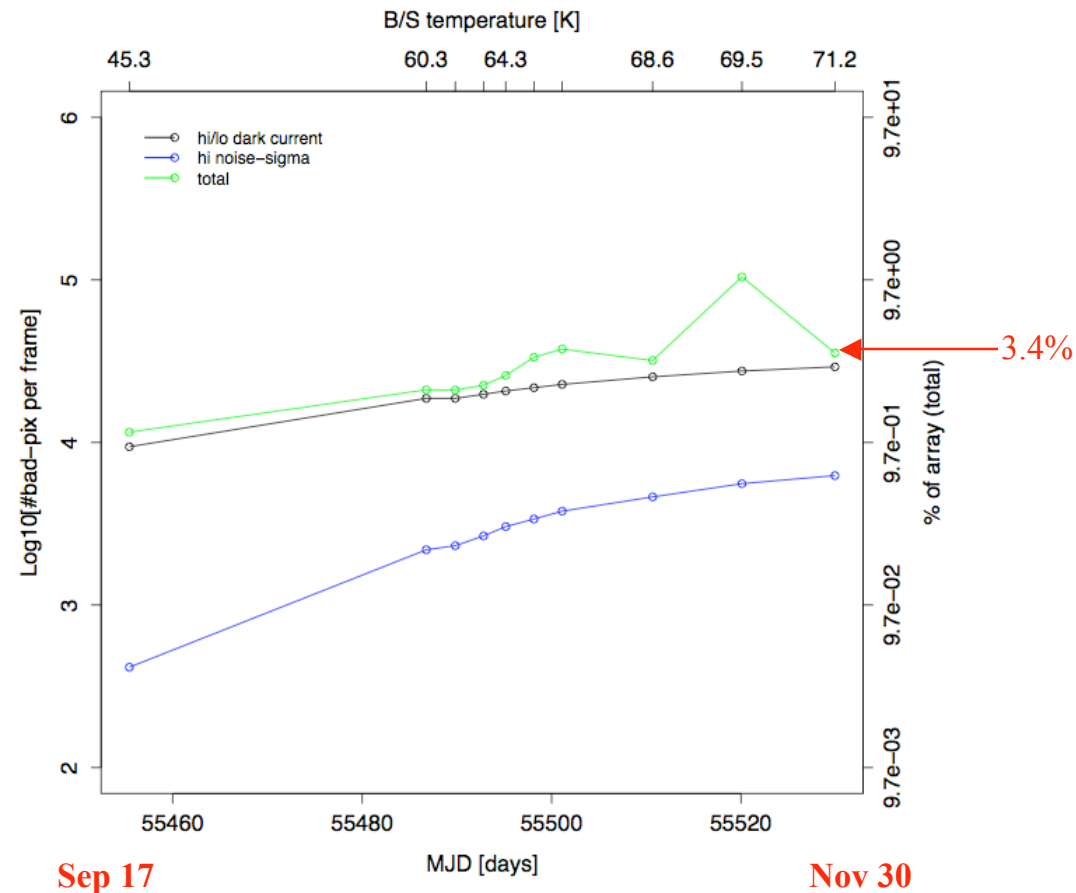
R. Cutri, T. Conrow, J. Bauer, R. Beck,  
D. Kirkpatrick, F. Masci, L. Yan



# W1 bad pixel trend



- used stacking analysis associated with dark and flat generation process
- thresholds defining “bad” pixels are (same for w1 and 2 and for all time):
  - hi/lo dark: *pixel stack median - global median* < -20 or > 500 DN;
  - hi noise: *robust pixel stack RMS* > 50 DN;

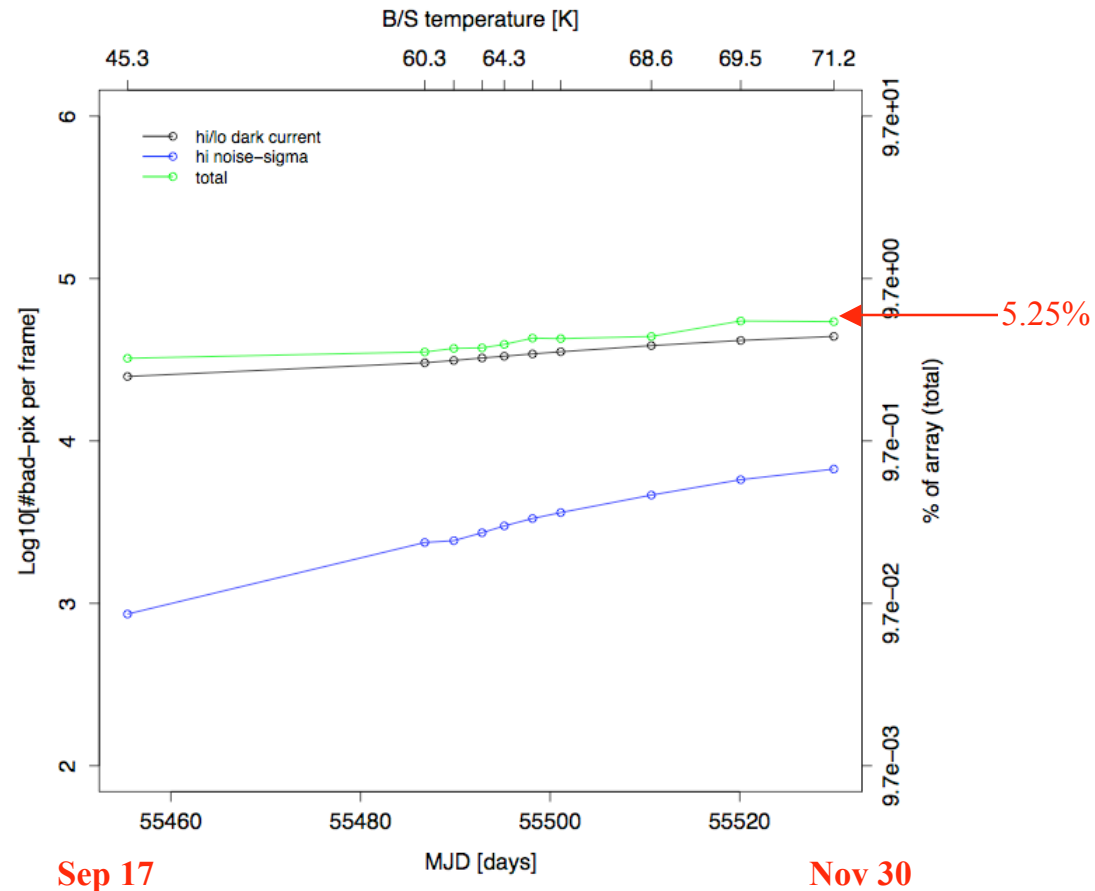




# W2 bad pixel trend



- used stacking analysis associated with dark and flat generation process
- thresholds defining “bad” pixels are (same for w1 and 2 and for all time):
  - hi/lo dark: *pixel stack median - global median* < -20 or > 500 DN;
  - hi noise: *robust pixel stack RMS* > 50 DN;



Sep 17

Nov 30